Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/707,684	CHEN ET AL.
Examiner	Art Unit
Tuan Quach	2826

SEARCHED					
Class	Subclass	Date	Examiner		
257	685, 686, 687, 712, 713, 717	2/16/2005	TQ		
257	777, 778	2/16/2005	TQ		
257	787, 796	2/16/2005	TQ		
438	122, 126	2/16/2005	TQ		
438	12,7	2/16/2005	TQ		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST (USPAT; USPGPUB; DERWNENT, EPO; JPO; IBMTDB)	2/16/2005	TQ
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